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Yvette C. Thornton

PTO/SB/21 (08-03)

Approved for use through 08/30/2003. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE or the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number. 10/079,289 **Application Number** TRANSMITTAL February 19, 2002 Filing Date **FORM** Ratnam SOORIYAKUMARAN First Named Inventor 1752 **Art Unit**

Examiner Name

Mail Stop PETITION		Attorney Docket Number Y	OR920000693US	52
		ENCLOSURES (Check all that apply)		
No fee due Fee Transmittal Fee(s) due Fee Transmittal Check for \$* Charge any underpayment credit any overpayment to Deposit Account No. 18-08 Return postcard Amendment/Reply After Final Affidavits/declaration(s) Extension of Time Request Express Abandonment Recults and Section Disclosure States Form(s) PTO-1449 Copy(ies) of cited reference(s) Certified Copy of Priority	or 580 s) t	ENCLOSURES (Check all that apply) Drawing(s) Licensing-related Papers Petition to Withdraw Holding of Abandonment Petition to Convert to a Provisional Application Power of Attorney, Revocation, Change of Correspondence Address Terminal Disclaimer Request for Refund CD, Number of CD(s): Remarks: The Commissioner is hereby authorize underpayment of fee(s) to Deposit Access	to a Technology Appeal Composition of Appeals Appeal Composition (Appeal Notice Proprietary Status Lette Other Enclopidentify below Support of Support of Control Cont	sure(s) (please pw): Statement in Petition
Document(s) Response to Missing Parts Incomplete Application Response to Missing under 37 CFR 1.52 o	Parts			
		URE OF APPLICANT, ATTORNEY, OR A	AGENT	
Firm or Individual Name (print/type)		anaan, Reg. No. 42,382 Eberle LLP	Telephone	(650) 330-0900
Signature	Ma	ren (quaan	Date	August 16, 2004
	/_	CERTIFICATE OF MAILING		
	-	CERTIFICATE OF MAILING		
hereby certify that this correspondence addressed to: Commissioner for Paten	e is being der its, P.O. Box	posited with the United States Postal Service with so 1450, Alexandria, VA 22313-1450 on the date show	ufficient postage as fir wn below.	st class mail in an envelope
Name (print/type) Mary O'M	lalley			
Signature Mo	سر٥	5.M.OQ	Date	August 16, 2004



In Re Application of:

Ratnam SOORIYAKUMARAN et al. Confirmation No.: 7983

Serial No.: 10/079,289 Group Art Unit: 1752

Filing Date: February 19, 2002 Examiner: Yvette C. THORNTON

Title: FLUORINATED SILSESQUIOXANE POLYMERS AND USE THEREOF IN

LITHOGRAPHIC PHOTORESIST COMPOSTIONS

PETITION TO WITHDRAW THE HOLDING OF ABANDONMENT UNDER 37 CFR § 1.181

Mail Stop Petition Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Applicants, by way of this Petition under 37 C.F.R. § 1.181 (the "Petition"), request withdrawal of the holding of abandonment for the above-identified application; this application was improperly held abandoned in the Notice of Abandonment mailed from the Office on June 28, 2004. The facts in support of the Petition are as follows.

STATEMENT OF FACTS

On September 23, 2003, a Restriction Requirement was sent from the United States Patent and Trademark Office (the "Office") for the application referenced above.

On October 23, 2003, a Third Preliminary Amendment and Response to Restriction Requirement was filed with the Office via first class mail.

On November 19, 2003, a Notice of Non-Compliant Amendment (the "Notice") was sent from the Office, stating that a complete listing of the claims was not included with the response. Applicants' were given one-month to respond to the Notice. The Notice is attached as Exhibit A.

On December 19, 2003, a Response to Non-Compliant Amendment (the "Response") was filed via first class mail. The Response is attached as Exhibit B.

Attached as Exhibit C is the "Transmittal Letter" submitted with the Response. The certificate of mailing on the Transmittal Letter shows that the Response was mailed prior to the expiration of the shortened statutory period for reply of one month set forth in the Notice, and within three months of the mailing date of the original Restriction Requirement.

Atty Dkt No. YOR920000693US2 Serial No. 10/079,289

Attached as Exhibit D is a statement by Mary O'Malley certifying that the Response was placed in the U.S. Mail on December 19, 2003.

Attached as Exhibit E is the return postcard submitted with the Response, which shows that the Response was received by the Office on December 22, 2003, and returned to Applicants, indicating that the USPTO received the Response.

The foregoing facts and supporting evidence demonstrate that the Response was timely and properly filed pursuant to 37 C.F.R. §1.8.

RELIEF REQUESTED

Because applicants mailed the Response prior to the expiration of the shortened statutory period for reply of one month as indicated by the certificate of mailing and return post card, the Response was timely and properly filed pursuant to 37 C.F.R. §1.8. Further, as this Petition is filed within two months of the mailing date of the Notice of Abandonment, applicants respectfully request withdrawal of the holding of abandonment in accordance with MPEP § 711.03(c).

Should the Commissioner have any questions regarding this matter, the undersigned attorney may be reached at (650) 330-0900.

As the Office does not charge a fee for Petitions to Withdraw the Holding of Abandonment, no fee accompanies this Petition. Should the Office determine that a fee is necessary to process this petition, then under such circumstance, the Commissioner is authorized to charge such fee to Deposit Account No. 18-0580.

Respectfully submitted,

Bv:

Karen Canaan

Registration No. 42,382

REED & EBERLE LLP 800 Menlo Avenue, Suite 210 Menlo Park, California 94025 (650) 330-0900 Telephone (650) 330-0980 Facsimile

F:\Document\5075\0029\20\Petition - Withdraw Abandonment.DOC



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.usplo.gov

APPL	ICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
1	0/079,289		02/19/2002	Ratnam Sooriyakumaran	YOR920000693US2	7983
2	3980	7590	11/19/2003		EXAM	INER .
	REED & E		LLP E, SUITE 210	RECEIVED	THORNTON	. YVETTE C
	ENLO PA		94025		ART UNIT	PAPER NUMBER

ENLO PARK, CA 94025

NOV 24 2013

REED & EBERLE LLP

1752 DATE MAILED: 11/19/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

PTO-90C (Rev. 10/03)

COMMISSIONER FOR PATENTS
UNITED STATES PATENT AND TRADEMARK OFFICE
P.O. BOX 1450

ALEXANDRIA, VA 22313-1450 www.uspto.gov

		Paper No.
	Notice of Non-Compliant Amendment (37 CFR 1.121)	
37 CFR be comp docume	endment document filed on <u>/// F/G</u> is considered non-compliant because it has failed to m 1.121, as amended on June 30, 2003 (see 68 Fed. Reg. 38611, Jun. 30, 2003). In order for the americant, correction of the following item(s) is required. Only the corrected section of the non-component must be resubmitted (in its entirety), e.g., the entire "Amendments to the claims" section of the non-component document must be re-submitted. 37 CFR 1.121(h).	ndment document to liant amendment
THE FO	DLLOWING CHECKED (X) ITEM(S) CAUSE THE AMENDMENT DOCUMENT TO BE NON- 1. Amendments to the specification: A. Amended paragraph(s) do not include markings. B. New paragraph(s) should not be underlined. C. Other	COMPLIANT:
	2. Abstract: ☐ A. Not presented on a separate sheet. 37 CFR 1.72. ☐ B. Other	
	3. Amendments to the drawings:	
	 4. Amendments to the claims: A. A complete listing of <u>all</u> of the claims is not present. B. The listing of claims does not include the text of all claims (including withdrawn claim C. Each claim has not been provided with the proper status identifier, and as such, the indiclaim cannot be identified. D. The claims of this amendment paper have not been presented in ascepding numerical on E. Other:	vidual status of each

For further explanation of the amendment format required by 37 CFR 1.121, see MPEP Sec. 714 and the USPTO website at http://www.uspto.gov/web/offices/pac/dapp/opla/preognotice/officeflyer.pdf.

If the non-compliant amendment is a **PRELIMINARY AMENDMENT**, applicant is given ONE MONTH from the mail date of this letter to supply the corrected section which complies with 37 CFR 1.121. Failure to comply with 37 CFR 1.121 will result in non-entry of the preliminary amendment and examination on the merits will commence without consideration of the proposed changes in the preliminary amendment(s). This notice is not an action under 35 U.S.C. 132, and this **ONE MONTH time limit** is not extendable.

If the non-compliant amendment is a reply to a NON-FINAL OFFICE ACTION (including a submission for an RCE), and since the amendment appears to be a bona fide attempt to be a reply (37 CFR 1.135(c)), applicant is given a TIME PERIOD of ONE MONTH from the mailing of this notice within which to re-submit the corrected section which complies with 37 CFR 1.121 in order to avoid abandonment. EXTENSIONS OF THIS TIME PERIOD ARE AVAILABLE UNDER 37 CFR 1.136(a).

If the amendment is a reply to a FINAL REJECTION, this form may be an attachment to an Advisory Action. The period for response to a final rejection continues to run from the date set in the final rejection, and is not affected by the non-compliant status of the amendment.

Legal Instruments Examiner (LIE)

Telephone No.

AUG. 2 0 2000 now, the Paperwork Reduction Act of 1995, no pe	rsons are required to respond to a collection		PTO/SB/21 (08-03) ugh 08/30/2003. OMB 0651-0031 DEPARTMENT OF COMMERCE DEPARTMENT OF COMMERCE
3	Application Number	10/079,289	says a valid Civib control number.
TRANSMITTAL FORM	Filing Date	February 19, 200	2
FORM	First Named Inventor	Ratnam Sooriyal	kumaran
(to be used for all correspondence after initial filing)	Art Unit	1752	
	Examiner Name	Yvette C. Thornto	
Mail Stop	Attorney Docket Number	YOR920000693U	S2
ENCL	OSURES (Check all that apply	<u>/)</u>	
No fee due	rawing(s) censing-related Papers etition etition to Convert to a rovisional Application ower of Attorney, Revocation, hange of Correspondence ddress rminal Disclaimer equest for Refund D, Number of CD(s):	After Allow to a Techr Appeal Cor of Appeals Appeal Cor (Appeal Notice Proprietary Status Lette Other Enclosidentify be	osure(s) (please low): y additional or
Response to Missing Parts under 37 CFR 1.52 or 1.53			
	APPLICANT, ATTORNEY, O	R AGENT	
	Reg. No. 31,292		
Individual Name (print/type) Reed & Eberle		Telephone	(650) 330-0900
Signature (M)	Elles	Date	December 19, 2003
	EDTIFICATE OF MAII INC		
I hereby certify that this correspondence is being deposited we envelope addressed to: Commissioner for Patents, P.O. Box	ERTIFICATE OF MAILING ith the United States Postal Service wit 1450, Alexandria, VA 22313-1450 on	th sufficient postage as fi the date shown below.	irst class mail in an
Name (print/type) Mary O'Malley			

Date

December 19, 2003

Signature



R&E No. 5075-0029,20

PTO/SB/17 (10-03)
Approved for use through 07/31/2006. OMB 0651-0032
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

FE	ΕT	RA	N	SM	IT	ΓΑΙ	
	fo	r F	Y	200	04		

Effective 10/01/2003. Patent fees are subject to annual revision.

Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT

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C	omplete if Known	
Application Number	10/079,289	
Filing Date	February 19, 2002	
First Named Inventor	Ratnam Sooriyakumaran	
Examiner Name	Yvette C. Thornton	
Art Unit	1752	
Attorney Docket No.	ARC920000693US2	

METHOD OF PAYMENT (check all that apply) FEE CALCULATION (continued)			
Check Credit card Money Other None	3. ADDITIONAL FEES		
Order Deposit Account:	Large Entity Small Entity		
Donasit	Fee Fee Fee Fee Description Fee Fee Fee Fee Description	D-14	
Account Number	1051 130 2051 65 Surcharge - late filing fee or oath	Paid	
Deposit International Business Machines Compretion	1052 50 2052 25 Surcharge - late provisional filing fee or	\dashv	
Account Name	cover sheet		
The Director is authorized to: (check all that apply)	1053 130 1053 130 Non-English specification 1812 2.520 1812 2.520 For filing a request for exparte reexamination		
Charge fee(s) indicated below Credit any overpayments	1804 920* 1804 920* Requesting publication of SIR prior to	$\neg \uparrow$	
Charge any additional fee(s) or any underpayment of fee(s)	Examiner action		
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to the above-identified deposit account.	1251 110 2251 55 Extension for reply within first month	\neg	
FEE CALCULATION	1252 420 2252 210 Extension for reply within second month		
1. BASIC FILING FEE Large Entity Small Entity	1253 950 2253 475 Extension for reply within third month		
Fee Fee Fee Fee Fee Description Fee Paid	1254 1,480 2254 740 Extension for reply within fourth month	\Box	
Code (\$) Code (\$) 1001 770 2001 385 Utility filing fee	1255 2.010 2255 1.005 Extension for reply within fifth month	\Box	
1002 340 2002 170 Design filing fee	1401 330 2401 165 Notice of Appeal		
1003 530 2003 265 Plant filing fee	1402 330 2402 165 Filing a brief in support of an appeal		
1004 770 2004 385 Reissue filing fee	1403 290 2403 145 Request for oral hearing		
1005 160 2005 80 Provisional filing fee	1451 1,510 1451 1,510 Petition to institute a public use proceeding	\neg	
SUBTOTAL (1) (\$) 0-	1452 110 2452 55 Petition to revive - unavoidable		
	1453 1,330 2453 665 Petition to revive - unintentional		
2. EXTRA CLAIM FEES FOR UTILITY AND REISSUE	E 1501 1,330 2501 665 Utility issue fee (or reissue)		
Extra Claims below Fee Paid			
Total Claims 84 -20** = 17 x 18 = \$306 Independent 2 2 2 2 2 2 2 2 2	1503 640 2503 320 Plant issue fee		
	1460 130 1460 130 Petitions to the Commissioner		
Multiple Dependent = 0	1807 50 1807 50 Processing fee under 37 CFR 1.17(q)		
Large Entity Small Entity Fee Fee Fee Fee Fee Description	1806 180 1806 180 Submission of Information Disclosure Stmt		
Code (\$) Code (\$)	8021 40 8021 40 Recording each patent assignment per property (times number of properties)	i	
1202 18 2202 9 Claims in excess of 20	1809 770 2809 385 Filing a submission after final rejection	\dashv	
1201 86 2201 43 Independent claims in excess of 3	(37 ČFR 1.129(a))	—	
1203 290 2203 145 Multiple dependent claim, if not paid 1204 86 2204 43 ** Reissue independent claims	1810 770 2810 385 For each additional invention to be examined (37 CFR 1.129(b))		
1204 86 2204 43 ** Reissue independent claims over original patent	1801 770 2801 385 Request for Continued Examination (RCE)	- 1	
1205 18 2205 9 ** Reissue claims in excess of 20 and over original patent	1802 900 1802 900 Request for expedited examination of a design application		
SUBTOTAL (2) (\$) 306.00	Other fee (specify)		
**or number previously paid, if greater; For Reissues, see above	*Reduced by Basic Filing Fee Paid SUBTOTAL (3) (\$) 0		

SUBMITTED BY			(Comple	te (if applicable))
Name (Print/Type)	Pianne E. Reed	Registration No. 31,292	Telepho	ne
Signature	Mann que		Date	December 19, 2003

WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038.

This collection of information is required by 37 CFR 1.17 and 1.27. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 12 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Confirmation No.: 7983

Ratnam SOORIYAKUMARAN et al.

Serial No.: 10/079,289

Group Art Unit: 1752

Filing Date: February 19, 2002

Examiner: Yvette C. THORNTON

Title: FLUORINATED SILSESQUIOXANE POLYMERS AND USE THEREOF IN LITHOGRAPHIC

PHOTORESIST COMPOSITIONS (as amended

herein)

THIRD PRELIMINARY AMENDMENT AND RESPONSE TO REQUIREMENT FOR RESTRICTION

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

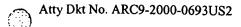
Sir:

This is in response to the Notice of Non-Compliant Amendment mailed November 19, 2003 concerning the patent application referenced above. This response includes a complete listing of the claims as required under 37 CFR 1.121, but otherwise, is a duplicate of the response mailed October 23, 2003. A copy of the Supplemental Information Disclosure Statement is also being resubmitted herewith.

An Amendment to the Title is set forth on page 2 of this document.

Amendments to the Claims are reflected in the listing of the claims which begins on page 3 of this document.

Remarks begin on page 14 of this document.



AMENDMENT TO THE TITLE

On page 1 of the application, at lines 1-2, on page 71 of the application, at lines 1-2, and wherever the title appears in the application documents, please change the title to read

<u>-FLUORINATED SILSESQUIOXANE POLYMERS AND</u>

<u>USE THEREOF IN LITHOGRAPHIC PHOTORESIST COMPOSITIONS--.</u>

BEST AVAILABLE COPY

Reply to Notice of Non-Compliant Amendment

The following listing of the claims will replace all prior versions, and listings, of claims in the application:

LISTING OF THE CLAIMS

Claims 1-66 (Canceled)

67. (Currently amended) A fluorinated silsesquioxane polymer comprised of monomer units having the structure (I)

wherein:

R¹, R², R³ and R⁴ are independently selected from the group consisting of substituents having-a terminal CR²R⁸R⁹-group the structure of formula -(Q)_n-CR⁷R⁸R⁹;

n is zero or 1;

Q is selected from the group consisting of arylene, substituted arylene, alkarylene, substituted alkarylene, and C_1 - C_4 alkylene optionally substituted with at least one nonhydrogen substituent selected from alkyl and fluoroalkyl;

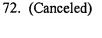
R⁷ is hydrogen, alkyl, or fluoroalkyl;

R⁸ is fluoroalkyl; and

R⁹ is OH, COOH or an acid-cleavable moiety.

- 68. (Canceled)
- 69. (Canceled)
- 70. (Canceled)

71. (Currently amended) The polymer of claim-69 67, wherein <u>n is 1 and Q</u> is selected from the group consisting of arylene, fluorinated arylene, eycloalkylene, fluorinated eycloalkylene, and C_1 - C_4 alkylene optionally substituted with 1-8 nonhydrogen substituents selected from alkyl and fluoroalkyl.



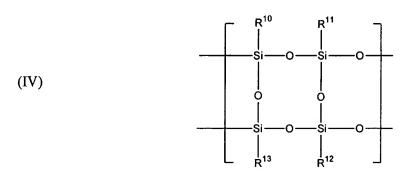
- 73. (Currently amended) The polymer of claim-72 71, wherein Q is arylene or fluorinated arylene.
- 74. (Canceled)
- 75. (Previously presented) The polymer of claim 73, wherein Q is arylene.
- 76. (Previously presented) The polymer of claim 73, wherein Q is fluorinated arylene.
- 77. (Canceled)
- 78. (Canceled)
- 79. (Previously presented) The polymer of claim 71, wherein Q is C₁-C₄ alkylene optionally substituted with 1-8 nonhydrogen substituents selected from alkyl and fluoroalkyl.
- 80. (Previously presented) The polymer of claim 79, wherein Q is C_1 - C_4 alkylene optionally substituted with 1-8 nonhydrogen substituents selected from C_1 - C_6 alkyl and C_1 - C_6 fluoroalkyl.
- 81. (Previously presented) The polymer of claim 79, wherein Q is C_1 - C_4 alkylene optionally substituted with 1-8 nonhydrogen substituents selected from C_1 - C_6 alkyl, trifluoromethyl, and trifluoromethyl-substituted C_1 - C_6 alkyl.
 - 82. (Canceled)
 - 83. (Canceled)
 - 84. (Previously presented) The polymer of claim 67, wherein R⁸ is C₁-C₆ fluoroalkyl.

Application Serial No. 10/079,289
Response dated December 19, 2
Reply to Notice of Non-Compliant Amendment

- 85. (Currently amended) The polymer of claim-83 84, wherein R^8 is trifluoromethyl-substituted C_1 - C_6 alkyl.
 - 86. (Previously presented) The polymer of claim 67, wherein R⁹ is OH.
 - 87. (Previously presented) The polymer of claim 67, wherein R⁹ is COOH.
 - 88. (Previously presented) The polymer of claim 67, wherein R⁹ is an acid-cleavable moiety.
- 89. (Previously presented) The polymer of claim 88, wherein the acid-cleavable moiety is an acid-cleavable ester, ether or carbonate.
 - 90. (Previously presented) The polymer of claim 89, wherein R⁹ is an acid-cleavable ester.
- 91. (Currently amended) The polymer of claim 90, wherein R⁹ has the formula -(L)_v-(CO)-OR¹⁴ wherein v is zero or 1, L is a linking group, and R¹⁴ is selected from the group consisting of <u>acyclic</u> tertiary alkyl moieties, cyclic-or-alicyclic substituents with a tertiary attachment point, and 2-trialkylsilylethyl moieties.
 - 92. (Currently amended) The polymer of claim 91, wherein v is zero and R¹⁴ is acyclic tertiary alkyl.
 - 93. (Previously presented) The polymer of claim 92, wherein R^{14} is t-butyl.
- 94. (Currently amended) The polymer of claim 91, wherein v is zero and R¹⁴ is a cyclic-or alieyelic substituent with a tertiary attachment point.
- 95. (Currently amended) The polymer of claim 94, wherein R¹⁴ is selected from the group consisting of adamantyl, norbornyl, isobornyl, 2-methyl-2-adamantyl, 2-methyl-2-isobornyl, 2-butyl-2-adamantyl, 2-propyl-2-isobornyl, 2-methyl-2-tetracyclododecenyl, 2-methyl-2-dihydrodicyclopentadienyl-cyclohexyl, 1-methylcyclopentyl, and 1-methylcyclohexyl, 2-trimethylsilylethyl, and 2-triethylsilylethyl.
 - 96. (Previously presented) The polymer of claim 91, wherein v is zero and R¹⁴ is 2-trialkylsilylethyl.



- 97. (Previously presented) The polymer of claim 96, wherein R¹⁴ is 2-trimethylsilylethyl.
- 98. (Previously presented) The polymer of claim 67, further comprising additional monomer units having the structure of formula (IV)



wherein R¹⁰, R¹¹, R¹² and R¹³ are independently hydrogen, alkyl, fluorocarbinol or an acidcleavable moiety, with the proviso that at least one of R¹⁰, R¹¹, R¹² and R¹³ is an acid-cleavable moiety.

- 99. (Currently amended) The polymer of claim 98, wherein at least one of R¹⁰, R¹¹, R¹² and R¹³ is are independently hydrogen, alkyl, or the acid-cleavable moiety, and the acid-cleavable moiety is selected from the group consisting of acid-cleavable esters, ethers, and carbonates.
- 100. (Previously presented) The polymer of claim 99, wherein at least one of R¹⁰, R¹¹, R¹² and R¹³ is an acid-cleavable ester.
- 101. (Previously presented) A lithographic photoresist composition comprising the fluorinated silsesquioxane polymer of claim 67 and a radiation-sensitive acid generator.
- 102. (Previously presented) A lithographic photoresist composition comprising the fluorinated silsesquioxane polymer of claim 98 and a radiation-sensitive acid generator.
- 103. (Previously presented) The lithographic photoresist composition of claim 101, wherein the photoresist composition is a positive resist and further comprises a photoacid-cleavable dissolution inhibitor.
- 104. (Previously presented) The lithographic photoresist composition of claim 102, wherein the photoresist composition is a positive resist and further comprises a photoacid-cleavable dissolution inhibitor.

Application Serial No. 10/079,227
Response dated December 19, 2
Reply to Notice of Non-Compliant Amendment

- 105. (Previously presented) The lithographic photoresist composition of claim 101, wherein the photoresist composition is a negative resist and further comprises a crosslinking agent.
- 106. (Previously presented) The lithographic photoresist composition of claim 102, wherein the photoresist composition is a negative resist and further comprises a crosslinking agent.
- 107. (Previously presented) The lithographic photoresist composition of claim 105, wherein the crosslinking agent is a glycoluril compound.
- 108. (Previously presented) The lithographic photoresist composition of claim 107, wherein the glycoluril compound is selected from the group consisting of tetramethoxymethyl glycoluril, methylpropyltetramethoxymethyl glycoluril, methylphenyltetramethoxymethyl glycoluril, and mixtures thereof.
- 109. (Previously presented) The lithographic photoresist composition of claim 106, wherein the crosslinking agent is a glycoluril compound.
- 110. (Previously presented) The lithographic photoresist composition of claim 109, wherein the glycoluril compound is selected from the group consisting of tetramethoxymethyl glycoluril, methylpropyltetramethoxymethyl glycoluril, methylphenyltetramethoxymethyl glycoluril, and mixtures thereof.
 - 111. (Withdrawn) A process for generating a resist image on a substrate, comprising the steps of:
 - (a) coating a substrate with a film of the photoresist composition of claim 101;
- (b) exposing the film selectively to a predetermined pattern of deep ultraviolet radiation so as to form a latent, patterned image in the film; and
 - (c) developing the latent image with a developer.
- 112. (Withdrawn) The process of claim 111, wherein the deep ultraviolet radiation has a wavelength of less than 250 nm.
- 113. (Withdrawn) The process of claim 112, wherein the deep ultraviolet radiation has a wavelength of 157 nm.

- 114. (Withdrawn) The process of claim 111, wherein the substrate is a bilayer substrate comprising a base layer covered by an underlayer and the photoresist composition covers the underlayer.
 - 115. (Withdrawn) A process for generating a resist image on a substrate, comprising the steps of:
 - (a) coating a substrate with a film of the photoresist composition of claim 102;
- (b) exposing the film selectively to a predetermined pattern of deep ultraviolet radiation so as to form a latent, patterned image in the film; and
 - (c) developing the latent image with a developer.
- 116. (Withdrawn) The process of claim 115, wherein the deep ultraviolet radiation has a wavelength of less than 250 nm.
- 117. (Withdrawn) The process of claim 116, wherein the deep ultraviolet radiation has a wavelength of 157 nm.
- 118. (Withdrawn) The process of claim 115, wherein the substrate is a bilayer substrate comprising a base layer covered by an underlayer and the photoresist composition covers the underlayer.
 - 119. (Withdrawn) A method of forming a patterned material structure on a substrate, comprising:
- (a) providing a substrate comprised of a material selected from the group consisting of semiconductors, ceramics and metals;
 - (b) applying a layer of the photoresist composition of claim 103 to the substrate;
- (c) patternwise exposing the substrate to radiation whereby acid is generated by the radiation-sensitive acid generator in exposed regions of the photoresist layer;
- (d) contacting the substrate with an aqueous alkaline developer solution, whereby the exposed regions of the photoresist layer are selectively dissolved by the developer solution to reveal a resist structure pattern; and
- (e) transferring the resist structure pattern to the substrate by etching into the substrate through spaces in the resist structure pattern.
 - 120. (Withdrawn) The process of claim 119, wherein the radiation is deep ultraviolet radiation.
 - 121. (Withdrawn) A method of forming a patterned material structure on a substrate, comprising:

- (a) providing a substrate comprised of a material selected from the group consisting of semiconductors, ceramics and metals;
 - (b) applying a layer of the photoresist composition of claim 104 to the substrate;
- (c) patternwise exposing the substrate to radiation whereby acid is generated by the radiation-sensitive acid generator in exposed regions of the photoresist layer;
- (d) contacting the substrate with an aqueous alkaline developer solution, whereby the exposed regions of the photoresist layer are selectively dissolved by the developer solution to reveal a resist structure pattern; and
- (e) transferring the resist structure pattern to the substrate by etching into the substrate through spaces in the resist structure pattern.
 - 122. (Withdrawn) The process of claim 119, wherein the radiation is deep ultraviolet radiation.
 - 123. (Withdrawn) A method of forming a patterned material structure on a substrate, comprising:
- (a) providing a substrate comprised of a material selected from the group consisting of semiconductors, ceramics and metals;
 - (b) applying a layer of the photoresist composition of claim 105 to the substrate
- (c) patternwise exposing the substrate to radiation whereby acid is generated by the radiation-sensitive acid generator in exposed regions of the photoresist layer thereby inducing crosslinking;
- (d) contacting the substrate with an aqueous alkaline developer solution, whereby the unexposed regions of the photoresist layer are selectively dissolved by the developer solution to reveal a negative resist structure pattern; and
- (e) transferring the negative resist structure pattern to the substrate by etching into the substrate through spaces in the negative resist structure pattern.
 - 124. (Withdrawn) A method of forming a patterned material structure on a substrate, comprising:
- (a) providing a substrate comprised of a material selected from the group consisting of semiconductors, ceramics and metals;
 - (b) applying a layer of the photoresist composition of claim 106 to the substrate
- (c) patternwise exposing the substrate to radiation whereby acid is generated by the radiation-sensitive acid generator in exposed regions of the photoresist layer thereby inducing crosslinking;
- (d) contacting the substrate with an aqueous alkaline developer solution, whereby the unexposed regions of the photoresist layer are selectively dissolved by the developer solution to reveal a negative resist structure pattern; and

- (e) transferring the negative resist structure pattern to the substrate by etching into the substrate through spaces in the negative resist structure pattern.
 - 125. (New) The polymer of claim 81, wherein Q is C₁-C₄ alkylene.
 - 126. (New) The polymer of claim 84, wherein R⁸ is trifluoromethyl.
- 127. (New) The polymer of claim 91, wherein v is 1 and L is selected from: linear, branched, and cyclic alkylene; linear, branched, and cyclic fluoroalkylene; and arylene.
- 128. (New) The polymer of claim 100, wherein the acid-cleavable ester has the formula -(L)_v-(CO)-OR¹⁴ wherein v is zero or 1, L is a linking group, and R¹⁴ is selected from the group consisting of acyclic tertiary alkyl moieties, cyclic substituents with a tertiary attachment point, and 2-trialkylsilylethyl moieties.
- 129. (New) The polymer of claim 128, wherein v is 1 and L is selected from: linear, branched, and cyclic alkylene; linear, branched, and cyclic fluoroalkylene; and arylene.
- 130. (New) The polymer of claim 129, wherein L is selected from linear, branched, and cyclic alkylene.
 - 131. (New) The polymer of 130, wherein L is cyclic alkylene.
 - 132. (New) The polymer of claim 131, wherein L is a norbornyl or cyclohexyl group.
 - 133. (New) The polymer of claim 132, wherein L is norbornyl.
 - 134. (New) The polymer of claim 131, wherein R¹⁴ is acyclic tertiary alkyl.
 - 135. (New) The polymer of claim 132, wherein R¹⁴ is acyclic tertiary alkyl.
 - 136. (New) The polymer of claim 133, wherein R¹⁴ is acyclic tertiary alkyl.
 - 137. (New) The polymer of claim 134, wherein R¹⁴ is t-butyl.

- 138. (New) The polymer of claim 135, wherein R^{14} is t-butyl.
- 139. (New) The polymer of claim 136, wherein R^{14} is t-butyl.
- 140. (New) The polymer of claim 131 wherein R¹⁴ is a cyclic substituent with a tertiary attachment point.
- 141. (New) The polymer of claim 132, wherein R¹⁴ is a cyclic substituent with a tertiary attachment point.
- 142. (New) The polymer of claim 133, wherein R¹⁴ is a cyclic substituent with a tertiary attachment point.
- 143. (New) The polymer of claim 140, wherein R¹⁴ is selected from the group consisting of adamantyl, norbornyl, isobornyl, 2-methyl-2-adamantyl, 2-methyl-2-isobornyl, 2-butyl-2-adamantyl, 2-propyl-2-isobornyl, 2-methyl-2-tetracyclododecenyl, 2-methyl-2-dihydrodicyclopentadienyl-cyclohexyl, 1-methylcyclopentyl, and 1-methylcyclohexyl.
- 144. (New) The polymer of claim 141, wherein R¹⁴ is selected from the group consisting of adamantyl, norbornyl, isobornyl, 2-methyl-2-adamantyl, 2-methyl-2-isobornyl, 2-butyl-2-adamantyl, 2-propyl-2-isobornyl, 2-methyl-2-tetracyclododecenyl, 2-methyl-2-dihydrodicyclopentadienyl-cyclohexyl, 1-methylcyclopentyl, and 1-methylcyclohexyl.
- 145. (New) The polymer of claim 144, wherein R¹⁴ is selected from the group consisting of adamantyl, norbornyl, isobornyl, 2-methyl-2-adamantyl, 2-methyl-2-isobornyl, 2-butyl-2-adamantyl, 2-propyl-2-isobornyl, 2-methyl-2-tetracyclododecenyl, 2-methyl-2-dihydrodicyclopentadienyl-cyclohexyl, 1-methylcyclopentyl, and 1-methylcyclohexyl.
 - 146. (New) The polymer of claim 131, wherein R¹⁴ is 2-trialkylsilylethyl.
 - 147. (New) The polymer of claim 132, wherein R¹⁴ is 2-trialkylsilylethyl.
 - 148. (New) The polymer of claim 133, wherein R¹⁴ is 2-trialkylsilylethyl.



- 149. (New) The polymer of claim 131, wherein R¹⁴ is 2-trialkylsilylethyl.
- 150. (New) The polymer of claim 147, wherein R¹⁴ is 2-trimethylsilylethyl.
- 151. (New) The polymer of claim 148, wherein R¹⁴ is 2-trimethylsilylethyl.
- 152. (New) The polymer of claim 151, wherein R¹⁴ is 2-trimethylsilylethyl.
- 153. (New) A copolymer comprised of fluorinated silsesquioxane monomer units having the structure (I)

and silsesquioxane comonomer units having the structure (IV)

(IV)
$$\begin{bmatrix} R^{10} & R^{11} \\ -S_{i} & O & S_{i} & O \\ 0 & O & O \\ -S_{i} & O & S_{i} & O \\ -S_{i} & O & S_{i} & O \end{bmatrix}$$

wherein:

R¹, R², R³ and R⁴ are independently selected from substituents of the formula -Q-CHR⁸R⁹;

Q is C₁-C₄ alkylene;

R⁸ is C₁-C₆ fluoroalkyl;

R⁹ is OH or COOH;

R¹⁰, R¹¹, R¹² and R¹³ are independently selected from the group consisting of hydrogen, alkyl, and acid-cleavable esters of the formula -L-(CO)-OR¹⁴, with the proviso that at least one of R¹⁰, R¹¹, R¹² and R¹³ is an acid-cleavable ester of the formula -L-(CO)-OR¹⁴;

L is a cycloalkylene linking group; and

R¹⁴ is selected from the group consisting of acyclic tertiary alkyl moieties, cyclic substituents with a tertiary attachment point, and 2-trialkylsilylethyl moieties.

154. (New) The copolymer of claim 153, wherein: R^8 is selected from trifluoromethyl and trifluoromethyl-substituted C_1 - C_6 alkyl; and R^9 is OH.

155. (New) The copolymer of claim 154, wherein:

R⁸ is trifluoromethyl;

R¹⁴ is selected from the group consisting of *t*-butyl, adamantyl, norbornyl, isobornyl, 2-methyl-2-adamantyl, 2-methyl-2-isobornyl, 2-methyl-2-tetracyclododecenyl, 2-methyl-2-dihydrodicyclopentadienyl-cyclohexyl, 1-methylcyclopentyl, 1-methylcyclohexyl, 2-trimethylsilylethyl, and 2-triethylsilylethyl.

156. (New) The copolymer of claim 155, wherein: L is norbornyl; and R^{14} is *t*-butyl.

- 157. (New) A lithographic photoresist composition comprising the copolymer of claim 153 and a radiation-sensitive acid generator.
- 158. (New) The lithographic photoresist composition of claim 157, wherein the photoresist composition is a positive resist and further comprises a photoacid-cleavable dissolution inhibitor.
- 159. (New) The lithographic photoresist composition of claim 157, wherein the photoresist composition is a negative resist and further comprises a crosslinking agent.

REMARKS

A. The Amendments:

The amendment to the title focuses on the subject matter of the elected claim group, i.e., on fluorinated silsesquioxane polymers (including copolymers) and photoresists containing the polymers. See Section B for applicants' election.

In the claims, claims 67, 71, 73, 85, 91, 92, 94, and 95 have been amended, claims 1-66, 68-70, 72, 74, 77, 78, 82, and 83 have been canceled, and new claims 125 through 159 have been added. Accordingly, claims 67, 71, 73, 75, 79-81, 84-159 are now pending, with claims 111-124 having been withdrawn. All claims, including the amended and new claims are within the elected group, except for withdrawn claims 111-124.

The amendments to claims 67, 71, 73, 85, 91, 92, 94, and 95 are as follows:

Claim 67 has been amended to specify R^7 as hydrogen and to incorporate the optional linker Q (from previously pending claim 68), wherein Q is arylene, substituted arylene, alkarylene, substituted alkarylene, or C_1 - C_4 alkylene optionally substituted with at least one nonhydrogen substituent selected from alkyl and fluoroalkyl (as previously recited in claim 69). Claim 71, 73, and 85 have been amended in light of the amendments to claim 67.

Claim 91 has been amended for clarification, since "alicyclic" groups and linkers are encompassed by the more generic term "cyclic," as is made clear in the specification (see, e.g., lines 6 and 7 of paragraph [0045]). Claims 92 and 94 have been amended in light of the amendment to claim 91.

Claim 95 has been amended to correct a minor and inadvertent error, and claim 99 has been amended solely for clarification.

The new claims are supported as follows:

Claims 125-127 are claims of intermediate scope further defining the subject matter of parent claims 81, 84, and 91, respectively, and supported in the specification at paragraphs [0019] and [0041]-[0044].

Claims 128 and 129 are analogous to claims 91 and 127, but depend from copolymer claim 100.

Claims 130-133 are directed to alkylene, cyclic alkylene, norbornyl or cyclohexyl, or norbornyl linking moieties "L," respectively, as set forth in paragraph [0045].

Claims 134-152 are directed to R¹⁴, and are supported in, for example, paragraph [0045].

Claim 153 is directed to a copolymer which is a subset of the copolymer recited in claim 98; claims 154-156 further refine the definitions of the various components, as recited in the specification and earlier claims.

Claims 157-159 are analogous to previously presented claims 102, 104, and 106, but depend from new copolymer claim 153.

Atty Dkt No. ARC9-2000-0693US2

Accordingly, no new matter has been added, and entry of the amendments and new claims is therefore proper.

B. The Requirement for Restriction:

Group (I), Claims 67-110, drawn to a fluorinated silsesquioxane polymer, a fluorinated silsesquioxane copolymer, and a photoresist composition thereof;

Group (II), Claims 111-118, drawn to a process for using the polymer and copolymer in generating a resist image on a substrate; and;

Group (III), Claims 119-124, drawn to a process for using the polymer and copolymer in forming a patterned material structure on a substrate.

Applicants elect Group (I) without traverse. Note that nonelected claims 111-118 have been canceled.

If the Examiner has any questions concerning this communication, or would like to discuss the application, the art, or other pertinent matters as search and examination are initiated, she is invited to contact the undersigned attorney at (650) 330-0900.

Respectfully submitted,

By:

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Ratnam SOORIYAKUMARAN et al.

Confirmation No.: 7983

Serial No.: 10/079,289

Group Art Unit: 1752

Filing Date: February 19, 2002

Examiner: Yvette C. Thornton

Title: SUBSTANTIALLY TRANSPARENT AQUEOUS BASE SOLUBLE POLYMER

SYSTEM FOR USE IN 157 NM RESIST APPLICATIONS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This is a duplicate of the Supplemental Information Disclosure Statement submitted October 23, 2003 for the Examiner's consideration. Applicants respectfully request that the Examiner review and make of record the references identified below.

A PTO-1449 form listing the references accompanies this paper. Applicants would appreciate the Examiner's initialing and returning the form to indicate that the references have been reviewed and made of record. The references are as follows:

	U.S. PATENT DOCUMENTS	
Document No.	Issue Date or Publication Date	Name of Patentee or Applicant
6,531,260	3/11/03	Iwasawa et al.
6,623,909	9/23/03	Hatakeyama et al.

This Information Disclosure Statement is not intended as a representation that additional information material to the examination of this application does not exist, or that any of the above references constitutes prior art to the present application within the meaning of 35 USC § 102.

Atty No. YOR920000693US2 Serial No. 10/079,289

As applicants have not yet received a first Action on the merits, no fee is required for filing this Information Disclosure Statement. If, however, the PTO finds that for some reason a fee is found to be necessary, Deposit Account No. 09-0441 may be charged therefore.

Respectfully submitted,

By:

Dianne E. Reed

Registration No. 31,292

REED & EBERLE LLP 800 Menlo Avenue, Suite 210 Menlo Park, California 94025 (650) 330-0900 Telephone (650) 330-0980 Facsimile Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	1	of	į

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Application Number	10/079,289			
Filing Date	February 19, 2002			
First Named Inventor	SOORIYAKURMARAN et al.			
Art Unit	1652			
Examiner Name	Unassigned			
Attorney Docket Number	YOR920000693US2			

U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.	Document No.	Issue Date or Publication Date	Name of Patentee or Applicant of Cited Document	Class	Subclass	Filing Date if Appropriate
	BR	6,531,260	3/11/03	Iwasawa et al.	İ		4/3/01
	BS	6,623,909	9/23/03	Hatakeyama et al.			6/1/01

Examiner	· ·	Date	
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Under the Panerwork Rev	duction Act of 1995, no person	U.S. Patent	and Tradamade Office, 110	PTO/SB/21 (08-03) ough 08/30/2003. OMB 0651-0031 DEPARTMENT OF COMMERCE	
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FORM		First Named Inventor	Ratnam Sooriyakumaran		
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		PLICANT, ATTORNEY, OR	RAGENT		
Firm or Individual Name (print/type)	Dianne E. Reed, Re Reed & Eberle LLP		Telephone	(650) 330-0900	
Signature	Voicnum El	mu Elled		December 19, 2003	
	AF5.	ICIOATE OF HAN OLD			
CERTIFICATE OF MAILING I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date shown below.					
Name (print/type) Mary O'M	alley				

Date

December 19, 2003

Signature





IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Ratnam SOORIYAKUMARAN et al. Co

Confirmation No.: 7983

Serial No.: 10/079,289

Group Art Unit: 1752

Filing Date: February 19, 2002

Examiner: Yvette C. THORNTON

E: FLUORINATED SILSESQUIOXANE POLYMERS AND USE THEREOF IN

LITHOGRAPHIC PHOTORESIST COMPOSTIONS

STATEMENT OF MARY O'MALLEY IN SUPPORT OF THE PETITION TO WITHDRAW THE HOLDING OF ABANDONMENT

Mail Stop Petitions Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

- I, Mary O'Malley, state the following:
- 1. I am a patent administrator for the law firm of Reed & Eberle LLP (formerly Reed & Associates) and have been acting in my capacity as such since August, 2002.
- 2. On December 19, 2003, I received the following documents for submission to the United States Patent and Trademark Office for the patent application identified above:
 - i. a Third Preliminary Amendment and Response to Requirement for Restriction; and
 - ii. an Information Disclosure Statement;
- 3. I prepared the Transmittal Form, Fee Transmittal, and a return postcard and gave the documents to attorney Dianne E. Reed for review and signature. After the signed documents were returned to me, I signed the certificate of mailing on the Transmittal Form, made copies of the documents, and placed the originals in an envelope addressed to the United States Patent and Trademark Office. I then placed the correct postage on the envelope, and placed the envelope in the outgoing mail basket for our law firm. The mail was picked up and hand-delivered to the nearest United States Postal Service office at 5:00 p.m.

4. Based on the foregoing sequence of events, I state that the Transmittal Form, Fee Transmittal, Response to the Notice of Non-Compliant Amendment, Information Disclosure Statement and return postcard for this patent application were timely filed on December 19, 2003.

Date: <u>Ougust</u> 16,2004

Name:__\

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5 Atty Dkt No.: Y	075-0029.20 0R920000693US2	Mailing Date:	December 19, 20	03
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	10/079,289	Filing Date:_	2/19/2002	-
Document(s):	Transmittal Form; Response to Non-C Information Discl	amaijani Awa	Humen	

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RADEMARK OFFICE

Atty Dkt No.:_	5075-0029.20 YOR920000693US2	Mailing Date: De	ecember 19, 2003
Inventor(s):	Ratnam Sooriyakumara	n et al.	
Serial No.:	10/079,289	Filing Date: 2/1	19/2002
Document(s):	Transmittal Form; Response to Non-C Information Discl Return Postcard	ompliant Amendme	ent
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